WITH 3-STATE OUTPUTS
SCAS330B – DECEMBER 1990 – REVISED OCTOBER 1998

- Low Output Skew, Low Pulse Skew for Clock-Distribution and Clock-Generation Applications
- TTL-Compatible Inputs and CMOS-Compatible Outputs
- Distributes One Clock Input to Eight Outputs
 - Four Same-Frequency Outputs
 - Four Half-Frequency Outputs
- Distributed V_{CC} and Ground Pins Reduce Switching Noise
- High-Drive Outputs (-48-mA I_{OH}, 48-mA I_{OL})
- State-of-the-Art EPIC-IIB™ BiCMOS Design Significantly Reduces Power Dissipation
- Package Options Include Plastic Small-Outline (DW)

DW PACKAGE (TOP VIEW) Y3 20 Y2 19 GND GND 18 Y1 Y4 3 17 VCC 16 CLK OE CLR 15 GND V_{CC} 14 VCC 13**∏** Q1 Q4 Π8 12 GND GND ∏9 Q3

description

The CDC337 is a high-performance, low-skew clock driver. It is specifically designed for applications requiring synchronized output signals at both the clock frequency and one-half the clock frequency. The four Y outputs switch in phase and at the same frequency as the clock (CLK) input. The four Q outputs switch at one-half the frequency of CLK.

When the output-enable (\overline{OE}) input is low and the clear (\overline{CLR}) input is high, the Y outputs follow CLK and the Q outputs toggle on low-to-high transitions at CLK. Taking \overline{CLR} low asynchronously resets the Q outputs to the low level. When \overline{OE} is high, the outputs are in the high-impedance state.

The CDC337 is characterized for operation from −40°C to 85°C.

FUNCTION TABLE

INPUTS			OUTPUTS		
ŌĒ	CLR	CLK	Y1-Y4	Q1-Q4	
Н	Х	Χ	Z	Z	
L	L	L	L	L	
L	L	Н	Н	L	
L	Н	L	L	Q ₀ †	
L	Н	\uparrow	Н	\overline{Q}_0^{\dagger}	

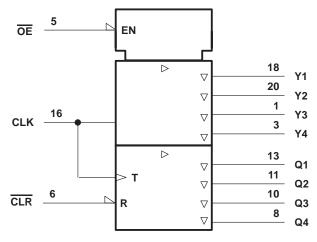
†The level of the Q outputs before the indicated steady-state input conditions were established

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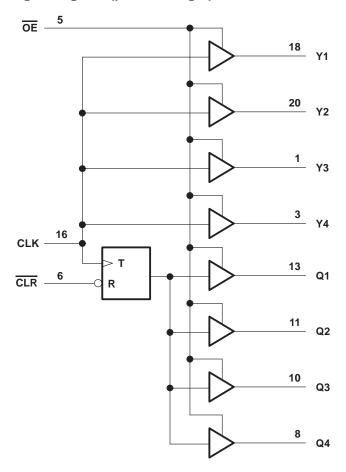


logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V_{CC}	
V _O (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Current into any output in the low state, IO	96 mA
Input clamp current, I_{IK} ($V_I < 0$)	–18 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2)	1.6 W
Storage temperature range, T _{stg}	–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.



^{2.} The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils. For more information, refer to the *Package Thermal Considerations* application note in the 1994 *ABT Advanced BiCMOS Technology Data Book*. literature number SCBD002B.

recommended operating conditions (see Note 3)

		MIN	MAX	UNIT
VCC	Supply voltage	4.75	5.25	V
VIH	High-level input voltage	2		V
V _{IL}	Low-level input voltage		0.8	V
VI	Input voltage	0	VCC	V
ІОН	High-level output current		-48	mA
lOL	Low-level output current		48	mA
f _{clock}	Input clock frequency		80	MHz
TA	Operating free-air temperature	-40	85	°C

NOTE 3: Unused pins (input or I/O) must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS			TYP [†]	MAX	UNIT
VIK	V _{CC} = 4.75 V,	I _I = -18 mA				-1.2	V
VOH	$V_{CC} = 4.75 \text{ V},$	$I_{OH} = -32 \text{ mA}$		3.75			V
V_{OL}	$V_{CC} = 4.75 V$,	$I_{OL} = 32 \text{ mA}$				0.55	V
lН	$V_{CC} = 5.25 \text{ V},$	V _I = 2.7 V				50	μΑ
I _{IL}	$V_{CC} = 5.25 \text{ V},$	V _I = 0.5 V				-50	μΑ
loz	$V_{CC} = 5.25 \text{ V},$	$V_O = V_{CC}$ or GND				±50	μΑ
	$V_{CC} = 5.25 \text{ V}, \qquad V_{I} = V_{CC} \text{ or GND}, I_{O} = 0$	$V_I = V_{CC}$ or GND, $I_O = 0$	Outputs high			70	
ICC			Outputs low			85	mA
		Outputs disabled			70		
C _i	V _I = 2.5 V or 0.5	$V_{I} = 2.5 \text{ V or } 0.5 \text{ V}$			3	·	pF
Co	$V_O = VCC \text{ or } GN$	D			10	·	pF

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

			MIN	MAX	UNIT
fclock	clock Clock frequency			80	MHz
		CLR low	4		
t _W	Pulse duration	CLK low	4		ns
		CLK high	4		
t _{su}	Setup time, CLR inactive before CLK↑		2		ns
	Clock duty cycle		40%	60%	



CDC337 CLOCK DRIVER WITH 3-STATE OUTPUTS SCAS330B – DECEMBER 1990 – REVISED OCTOBER 1998

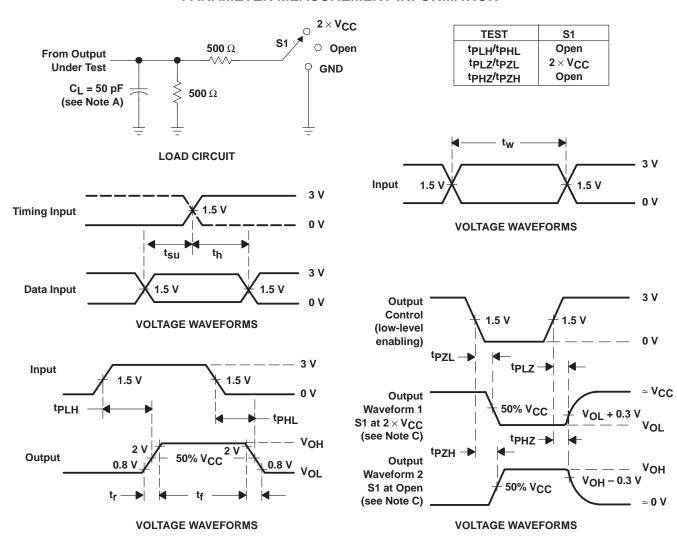
switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Note 4 and Figures 1 and 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	TYPT N	IAX	UNIT
fmax			80			MHz
t _{PLH}	CLK	Any Y or Q	4		9	ns
t _{PHL}			4		9	115
t _{PHL}	CLR	Any Q	4		10	ns
^t PZH	ŌĒ	Any Var O	3		7	
^t PZL		Any Y or Q	3		7	ns
^t PHZ		Amy V or O	2		7	no
t _{PLZ}	ŌĒ	Any Y or Q	2		7	ns
	clk↑	Y↑		().75	
^t sk(o)		Q↑			0.9	ns
		Y↑ and Q↑			0.9	
t _r				0.9		ns
t _f				0.7		ns

† All typical values are at V_{CC} = 5 V, T_A = 25°C. NOTE 4: All specifications are valid only for all outputs switching.



PARAMETER MEASUREMENT INFORMATION



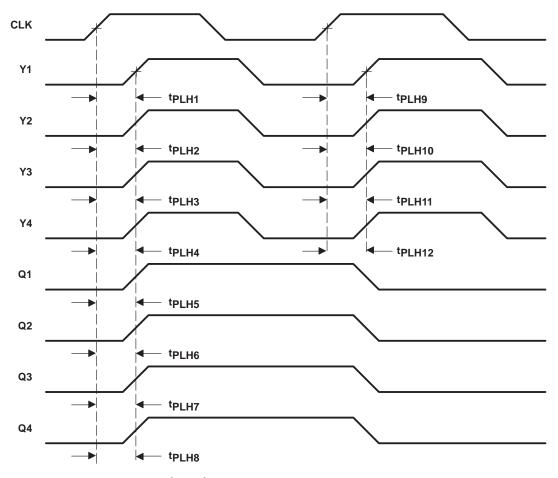
NOTES: A. C_I includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION



- NOTES: A. Output skew, t_{sk(o)}, from CLK↑ to Y↑, is calculated as the greater of the difference between the fastest and slowest of tpLHn (n = 1, 2, 3, 4) or tpLHn (n = 9, 10, 11, 12).
 B. Output skew, t_{sk(o)}, from CLK↑ to Q↑, is calculated as the greater of the difference between the fastest and slowest of tpLHn (n = 5, 6, 7, 8).

 - C. Output skew, $t_{sk(0)}$, from CLK \uparrow to Y \uparrow and Q \uparrow , is calculated as the greater of the difference between the fastest and slowest of t_{PLHn} (n = 1, 2, ..., 8).

Figure 2. Waveforms for Calculation of t_{sk(o)}

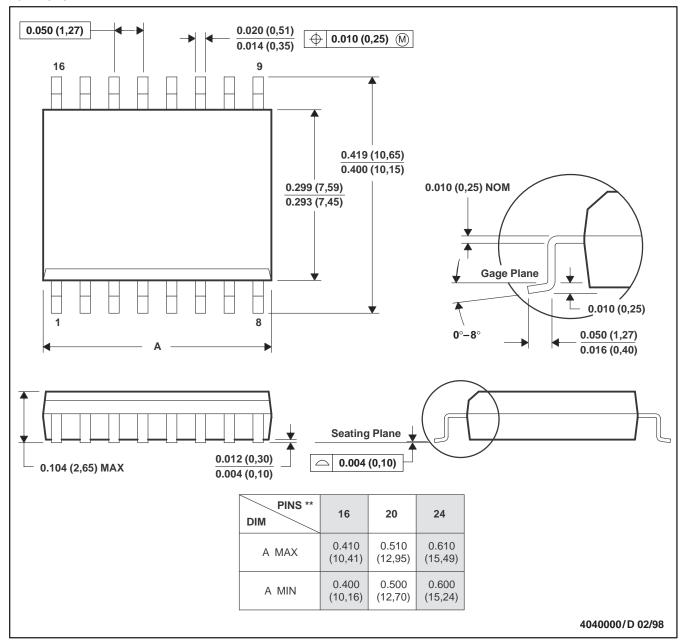


MECHANICAL INFORMATION

DW (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

16 PIN SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013



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